

STD40NF06

N-CHANNEL 60V - 0.024 Ω - 40A DPAK STripFETTM II POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STD40NF06	60 V	<0.028 Ω	40 A

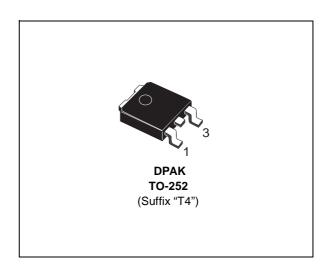
- TYPICAL $R_{DS}(on) = 0.024 \Omega$
- EXCEPTIONAL dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- SURFACE-MOUNTING DPAK (TO-252)
 POWER PACKAGE IN TAPE & REEL (SUFFIX "T4")

DESCRIPTION

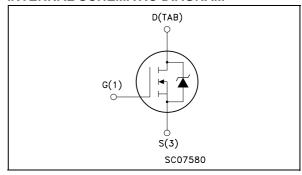
This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

APPLICATIONS

- HIGH CURRENT, HIGH SWITCHING SPEED
- MOTOR CONTROL, AUDIO AMPLIFIERS
- SOLENOID AND RELAY DRIVERS
- DC-DC & DC-AC CONVERTERS



INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	60	V
V_{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	60	V
V _{GS}	Gate- source Voltage	± 20	V
I _D	Drain Current (continuous) at T _C = 25°C	40	A
I _D	Drain Current (continuous) at T _C = 100°C	28	A
I _{DM} (•)	Drain Current (pulsed)	160	A
P _{tot}	Total Dissipation at T _C = 25°C	85	W
	Derating Factor	0.57	W/°C
dv/dt(1)	Peak Diode Recovery voltage slope	10	V/ns
E _{AS} (2)	Single Pulse Avalanche Energy	250	mJ
T _{stg}	Storage Temperature	55 to 175	
Tj	Operating Junction Temperature	-33 to 173	°C

^(•) Pulse width limited by safe operating area.

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⁽¹⁾ I_{SD} \leq 40A, di/dt \leq 300A/µs, V_{DD} \leq V_{(BR)DSS}, T_j \leq T_{JMAX} (2) Starting T_j = 25 °C, I_D = 20 A, V_{DD} = 30 V

THERMAL DATA

Rthj-case Rthj-pcB T _I Thermal Resistance Junction-case Thermal Resistance Junction-PCB (#) Maximum Lead Temperature For Soldering Purpose	Max Max	1.76 50 275	°C/W °C/W °C
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^(#) When Mounted on 1 inch2 FR-4 board, 2 oz Cu.

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0$	60			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating T_C = 100$ °C			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	2		4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V	I _D = 20 A		0.024	0.028	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	$V_{DS} = 30 \text{ V}$ $I_{D} = 20 \text{ A}$		13		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1 MHz$, $V_{GS} = 0$		920 225 80		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{array}{ccc} V_{DD} = 30 \text{ V} & I_D = 20 \text{ A} \\ R_G = 4.7 \; \Omega & V_{GS} = 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{array}$		11 50		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 48V I _D = 40A V _{GS} = 10V		32 6.5 15	43	nC nC nC

SWITCHING OFF

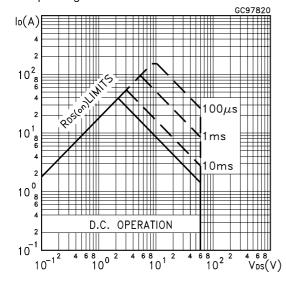
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time	$\begin{aligned} &V_{DD} = 30 \text{ V} & I_{D} = 20 \text{ A} \\ &R_{G} = 4.7\Omega, & V_{GS} = 10 \text{ V} \\ &(\text{Resistive Load, Figure 3}) \end{aligned}$		27 11		ns ns

SOURCE DRAIN DIODE

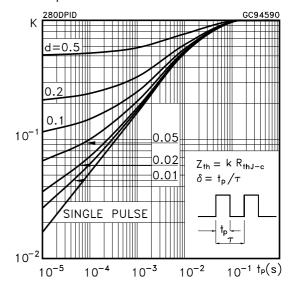
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (•)	Source-drain Current Source-drain Current (pulsed)				40 160	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 40 A V _{GS} = 0			1.3	V
t _{rr} Q _{rr} IRRM	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$\begin{split} I_{SD} = 40 \text{ A} & \text{di/dt} = 100 \text{A/µs} \\ V_{DD} = 10 \text{ V} & T_j = 150 ^{\circ}\text{C} \\ \text{(see test circuit, Figure 5)} \end{split}$		63 150 4.8		ns nC A

^(*)Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

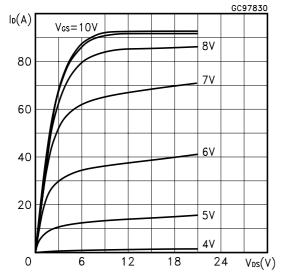
Safe Operating Area



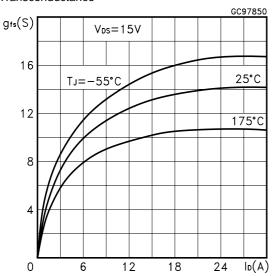
Thermal Impedance



Output Characteristics

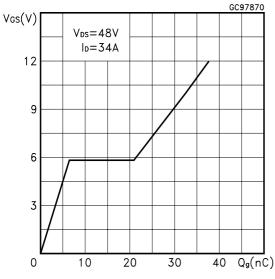


Transconductance

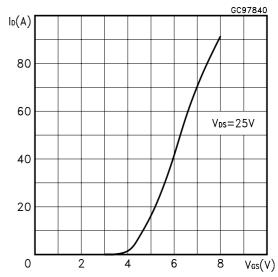


Gate Charge vs Gate-source Voltage

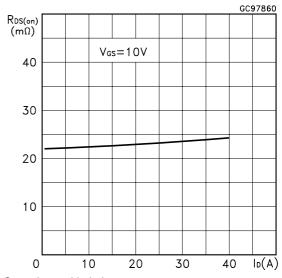
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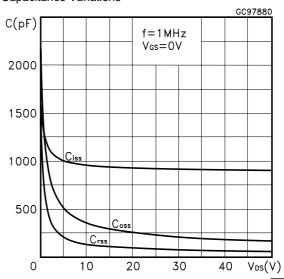
Transfer Characteristics



Static Drain-source On Resistance

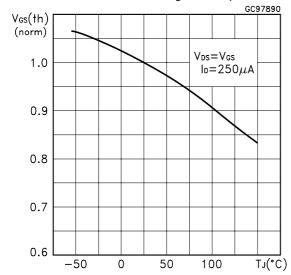


Capacitance Variations

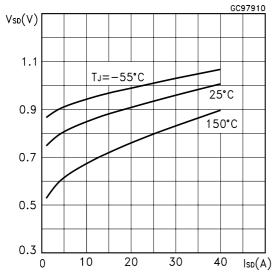


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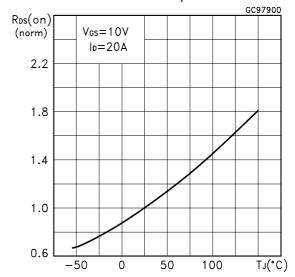
Normalized Gate Threshold Voltage vs Temperature



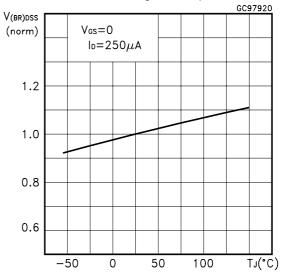
Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature.



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Fig. 1: Unclamped Inductive Load Test Circuit

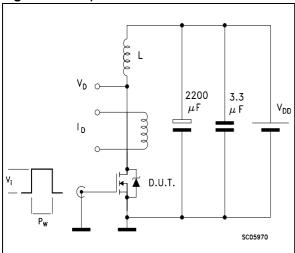


Fig. 3: Switching Times Test Circuits For Resistive Load

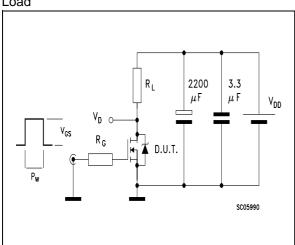


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

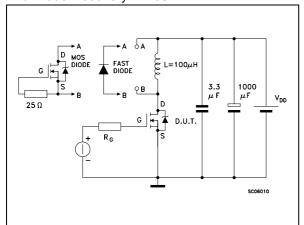


Fig. 2: Unclamped Inductive Waveform

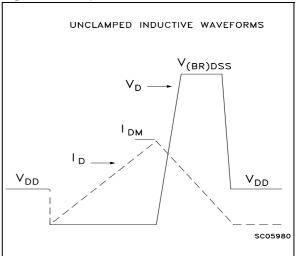
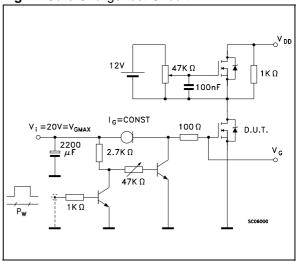
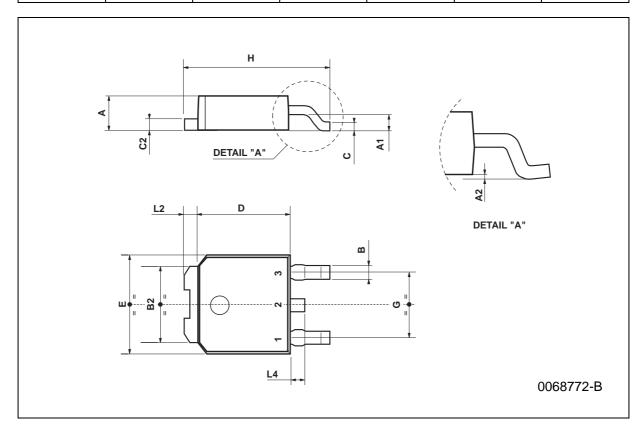


Fig. 4: Gate Charge test Circuit



TO-252 (DPAK) MECHANICAL DATA

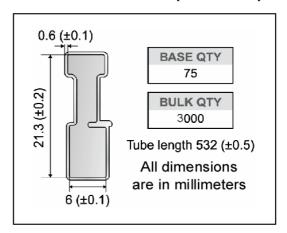
DIM.		mm	mm		inch		
Dilli.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	2.2		2.4	0.086		0.094	
A1	0.9		1.1	0.035		0.043	
A2	0.03		0.23	0.001		0.009	
В	0.64		0.9	0.025		0.035	
B2	5.2		5.4	0.204		0.212	
С	0.45		0.6	0.017		0.023	
C2	0.48		0.6	0.019		0.023	
D	6		6.2	0.236		0.244	
E	6.4		6.6	0.252		0.260	
G	4.4		4.6	0.173		0.181	
Н	9.35		10.1	0.368		0.397	
L2		0.8			0.031		
L4	0.6		1	0.023		0.039	



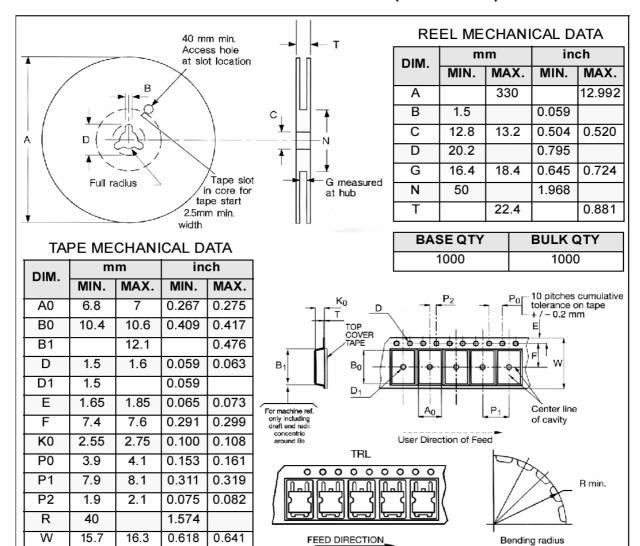
DPAK FOOTPRINT

6.7 1.8 3.0 1.6 2.3 1.6 All dimensions are in millimeters

TUBE SHIPMENT (no suffix)*



TAPE AND REEL SHIPMENT (suffix "T4")*



^{*}on sales type

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